Compliant with IEC 62474/ D9.00

MICROCHIP Semiconductor Device Type:	(T4X) 044 TQFP 10x10x1mm Matte Tin	Termination Base Alloy: Copper Alloy (Cu)			Package Homogeneous Materials				JEDEC 97 Product Marking and/or Pkg. Labeling e3	
		"Contained In"	% I otal			218.09	(mg) Total	Mold Compound	% ot Total Weight	79.8
Basic Substance	CAS Number	Sub-Component	Weight	mg/part	ppm	210.09	(ilig) Total	•	% of Total Weight	79.0
Silica, vitreous	60676-86-0	Mold Compound	69.354	189.545	693,542		Silica, vitreous	60676-86-0	86.91	
Epoxy Resin	Trade Secret	Mold Compound	6.121	16.728	61,207		Epoxy Resin	Trade Secret	7.67	
Phenolic Resin	Trade Secret	Mold Compound	4.078 0.247	11.145	40,778		Phenolic Resin	Trade Secret	5.11	
Carbon Black	1333-86-4 7440-50-8	Mold Compound	10.000	0.676 27.331	2,474 100,003		Carbon Black	1333-86-4	0.31	
Copper Nickel	7440-50-8	Lead Frame Lead Frame	0.267	0.729	2.667	28.70	(mm) Tatal	Total Lead Frame		10.5
Silver	7440-02-0	Lead Frame	0.267	0.729	1,752	28.70	(mg) Total	7440-50-8	% of Total Weight 95.24	10.5
Silicon	7440-22-4	Lead Frame	0.175	0.479	473		Copper Nickel	7440-50-8	2.54	
Magnesium	7439-95-4	Lead Frame	0.047	0.029	105		Silver	7440-22-4	1.67	
Silver (Aa)	7440-22-4	Die Attach	0.600	1.640	6,000		Silicon	7440-21-3	0.45	
Acrylate Urethane Oligomer	General	Die Attach	0.150	0.410	1,500		Magnesium	7439-95-4	0.10	
Silicon	7440-21-3	Chip (Die)	7.500	20,498	75.000			Total		
Copper	7440-50-8	Wire Bond palladium coated copper (CuPd)	0.197	0.537	1.965	2.05	(mg) Total	Die Attach	% of Total Weight	0.75
Palladium	7440-05-3	Wire Bond palladium coated copper (CuPd)	0.004	0.010	35		Silver (Ag)	7440-22-4	80	
Tin	7440-31-5	Plating on external leads (pins) - Matte Tin / annealed at 150°C for 1 hour	1.250	3.416	12,500		Acrylate Urethane Oligomer	er General	20	
		TOTALS:	100.000	273.300	1,000,000			Total	100.00	
	0 2733	g Total Mass				20.50	Total (mg)	Chip (Die)	% of Total Weight	7.5
5) and 2002/53/EC (End-of-Life Vehicles (ELV) without exemption	(zero)	2002/95/EC (27 January 2003) & Directive 2011/65/EU (0	8 June 2011) a	nd 2015/863/E	U (31 March		Doped Silicon	7440-21-3	100 100.00	
15) and 2002/53/EC (End-of-Life Vehicles (ELV) without exemption impliance with the above EU Directives has been verified via inter- ic chemical substance is absent from the list above, the chemical storporated's knowledge and belief as of the date of this document	(zero) nal design contro ubstance is NOT , there is no cred	2002/95/EC (27 January 2003) & Directive 2011/65/EU (0 ls, supplier declarations, and /or analytical test data. an intentional ingredient in the semiconductor device and ble reason to believe that the unavoidable impurity conce	, to the best o	f Microchip Te	chnology	0.55		7440-21-3 Total Wire Bond palladium coated		0.2
(5) and 2002/53/EC (End-of-Life Vehicles (ELV) without exemption impliance with the above EU Directives has been verified via interichemical substance is absent from the list above, the chemical sorporated's knowledge and belief as of the date of this document y, is not below the threshold of regulatory concern for any regulating compounds used by Microchip meet the UL94 V0 flammabiling.	(zero) nal design contro ubstance is NOT , there is no cred ory scheme worl ity standard for p	2002/95/EC (27 January 2003) & Directive 2011/65/EU (0 ls, supplier declarations, and /or analytical test data. an intentional ingredient in the semiconductor device and ble reason to believe that the unavoidable impurity conced-wide.	, to the best of	f Microchip Te chemical sub	chnology	0.55	Doped Silicon	7440-21-3 Total Wire Bond	100.00	0.2
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15) and 2002/53/EC (End-of-Life Vehicles (ELV) without exemption impliance with the above EU Directives has been verified via internance with the above EU Directives has been verified via internance in chemical substance is absent from the list above, the chemical substance is absent from the list above, the chemical substance is absent from the date of this document y, is not below the threshold of regulatory concern for any regulate yiding compounds used by Microchip meet the UL94 V0 flammabil p://ul.com/global/eng/pages/offerings/industries/chemicals/plastice protective "tubes" in which the specific product is shipped are respective to the specific product is shipped are respective.	(zero) nal design contro ubstance is NOT , there is no cred ory scheme worl ity standard for p iss/ nade from polyvi form concerning unowledge and be compiled based some information odd the average wi	2002/95/EC (27 January 2003) & Directive 2011/65/EU (0 ls, supplier declarations, and /or analytical test data. an intentional ingredient in the semiconductor device and ble reason to believe that the unavoidable impurity concedivide. lastics. You can access the UL iQTM family of databases the lastics. You can access the UL iQTM family of databases the lastics of the lastics. Will have a lastic of the la	, to the best of intration of the o obtain a test old the packing incorporated's gy Incorporate vided by raw n and raw mater	f Microchip Te chemical sub- t report at g slip on the o semiconducto d cannot guar naterial supplies. I	chnology stance, if uter box and or devices in antee the ers. Supplier nformation	0.55	Doped Silicon (mg) Total Copper	7440-21-3 Total Wire Bond palladium coated copper (CuPd) 7440-50-8	100.00 % of Total Weight 98	0.2
15) and 2002/53/EC (End-of-Life Vehicles (ELV) without exemption impliance with the above EU Directives has been verified via international chemical substance is absent from the list above, the chemical substance is absent from the list above, the chemical substance is absent from the list above, the chemical substance is absent from the list above, the chemical substance is absent from the list above, the chemical substance is of the date of this document y, is not below the threshold of regulatory concern for any regulation of the list of	(zero) nal design contro ubstance is NOT , there is no cred ory scheme worl ity standard for p ss/ made from polyvi form concerning mowledge and b compiled based some information of the average w silicon devices (s express or implie ubsidiaries are c	2002/95/EC (27 January 2003) & Directive 2011/65/EU (0 ls, supplier declarations, and /or analytical test data. an intentional ingredient in the semiconductor device and ble reason to believe that the unavoidable impurity conced-wide. Ilastics. You can access the UL iQTM family of databases the lastics. You can access the UL iQTM family of databases the lastics. You can access the UL iQTM family of databases the lastics. You can access the UL iQTM family of databases the lastics. You can access the UL iQTM family of databases the lastics. You can access the UL iQTM family of databases the lastics. You can access the UL iQTM family of databases the listing family of databases the lastics. You can access the UL iQTM family of databases the listing family of	, to the best of intration of the o obtain a test old the packing incorporated's gy incorporate vided by raw n and raw mater 'hese estimate tion. The exclusiale. These are	f Microchip Te chemical sub- t report at g slip on the o semiconductor d cannot guar naterial suppli- ial suppliers. I se do not inclu- usive, limited p e provided in I	chnology stance, if uter box and or devices in antee the ers. Supplier nformation de trace oroduct Microchip's	0.55	Doped Silicon (mg) Total Copper	7440-21-3 Total Wire Bond palladium coated copper (CuPd) 7440-50-8 7440-05-3	100.00 % of Total Weight 98	1.25
15) and 2002/53/EC (End-of-Life Vehicles (ELV) without exemption impliance with the above EU Directives has been verified via interral chemical substance is absent from the list above, the chemical substance is absent from the list above, the chemical substance is absent from the list above, the chemical substance is absent from the list above, the chemical substance is approached. It is above, the chemical substance is a propertied in the list above, the chemical substance is a propertied in the list above, the list is propertied in the list and compounds used by Microchip meet the UL94 V0 flammabil p://ul.com/global/eng/pages/offerings/industries/chemicals/plastic product is "tubes" in which the specific product is shipped are ration "reels" may be made from PVC plastic. Crochip Technology Incorporated believes the information in this ieir original packing materials is true and correct to the best of its impleteness and accuracy of data in this form because it has been approvided only as estimates of the average weight of these parts are les of dopants, metals, and non-metal materials contained within crochip Technology Incorporated does not provide any warranty, rranties provided by Microchip Technology Incorporated and its second	(zero) nal design contro ubstance is NOT , there is no cred ory scheme worl ity standard for p ss/ nade from polyvi form concerning unowledge and be compiled based some information of the average w silicon devices (s express or implie ubsidiaries are c to Material Conte reliance on the in	2002/95/EC (27 January 2003) & Directive 2011/65/EU (0 ls, supplier declarations, and /or analytical test data. an intentional ingredient in the semiconductor device and ble reason to believe that the unavoidable impurity conced-wide. Ilastics. You can access the UL iQTM family of databases the lastics. You can access the UL iQTM family of databases the unit of the lastics. You can access the UL iQTM family of databases the lastics. You can access the UL iQTM family of databases the lastics. You can access the UL iQTM family of databases the lastics of the lastics. "Window envelopes" used to have lasticated in this form. Microchip Technology I lilef, as of the date listed in this form. Microchip Technology on the ranges provided in Material Safety Data Sheets promay not have been provided by subcontract assemblers inglift of anticipated significant toxic metals components. Tallicon IC) in the finished parts. d, with respect to the information provided in this declaration in Microchip's standard terms and conditions of the Declarations and shall not be liable for any damages, difformation in Material Content Declarations (MCD) or independent of the lastic part of the last	to the best of intration of the oobtain a test old the packing incorporated's gy Incorporate vided by raw in and raw mater hese estimate tion. The exclusiale. These arrect or indirect or indirect or the test of the sale.	f Microchip Te chemical sub- t report at g slip on the o semiconducto d cannot guar naterial suppliers. I is do not inclu- usive, limited p e provided in I t, consequenti	chnology stance, if uter box and or devices in antee the ers. Supplier information de trace		(mg) Total Copper Palladium	7440-21-3 Total Wire Bond palladium coated copper (CuPd) 7440-50-8 7440-05-3 Total Plating on external leads (pins) - Matte Tin / annealed at 150°C for 1	100.00 % of Total Weight 98 2 100.00 % of Total Weight 100.00	

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